## **Power MOSFET**

# 30 V, 26 A, Single N-Channel, μ8FL

### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

### **Applications**

- DC-DC Converters
- Point of Load
- Power Load Switch
- Notebook Battery Management
- Motor Control

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Paran	Symbol	Value	Unit		
Drain-to-Source Voltage	$V_{DSS}$	30	V		
Gate-to-Source Voltage	$V_{GS}$	±20	V		
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	7.3	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C	1	5.3	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.2	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	10.3	Α
Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T <sub>A</sub> = 85°C		7.5	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	4.4	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	4.6	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C		3.3	
Power Dissipation R <sub>0JA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.84	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	26	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C	1	19	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	27.8	W
Pulsed Drain Current	T <sub>A</sub> = 25°	C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	77	Α
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Source Current (Body Die	I <sub>S</sub>	23	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-So $(T_J = 25^{\circ}C, V_{DD} = 50 \text{ V}, \text{V}_{L} = 18.3 \text{ A}_{pk}, L = 0.1 \text{ mH}$	E <sub>AS</sub>	16.7	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

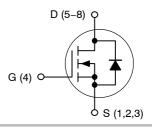


### ON Semiconductor®

### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX	
30 V	24 mΩ @ 10 V	26 A	
	36 mΩ @ 4.5 V	2014	

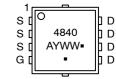
### **N-Channel MOSFET**





CASE 511AB

# **MARKING DIAGRAM**



4840 = Specific Device Code Α = Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTTFS4840NTAG	WDFN8 (Pb-Free)	1500/Tape & Reel
NTTFS4840NTWG	WDFN8 (Pb-Free)	5000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.5	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{ heta JA}$	57.5	
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	149.2	
Junction-to-Ambient – (t $\leq$ 10 s) (Note 3)	$R_{ heta JA}$	28.7	

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition	on	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				-	•	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				17		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			1.0	μΑ
			T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> =	±20 V			±100	nA
ON CHARACTERISTICS (Note 5)			•				•
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 2$	250 μΑ	1.5		3.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub> V <sub>GS</sub> = 10 V to 11.5 V		I <sub>D</sub> = 20 A		15	24	mΩ
		I <sub>D</sub> = 10 A		15			
		V 45V	I <sub>D</sub> = 20 A		28	36	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 10 A		25		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 20 A			22		S
CHARGES AND CAPACITANCES							-
Input Capacitance	C <sub>iss</sub>				580		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 15 V			140		
Reverse Transfer Capacitance	C <sub>rss</sub>				80		
Total Gate Charge	Q <sub>G(TOT)</sub>				5.5		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				0.75		
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15$	V, I <sub>D</sub> = 20 A		2.2		
Gate-to-Drain Charge	$Q_{GD}$		Ī		2.8		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 20 A			10.8		nC
SWITCHING CHARACTERISTICS (No	ote 6)						
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			10.5		ns
Rise Time	t <sub>r</sub>				38.2		
Turn-Off Delay Time	t <sub>d(off)</sub>				11.5		
Fall Time	t <sub>f</sub>				2.6		

<sup>5.</sup> Pulse Test: pulse width = 300  $\mu$ s, duty cycle  $\leq$  2%.

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

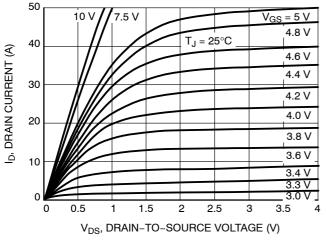
<sup>6.</sup> Switching characteristics are independent of operating junction temperatures.

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTIC	S (Note 6)				•	•	
Turn-On Delay Time	t <sub>d(on)</sub>				6.3		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> :	= 15 V,		19.4		1
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D = 15 \text{ A}, R_G =$			15.8		1
Fall Time	t <sub>f</sub>				1.7		1
DRAIN-SOURCE DIODE CHARA	ACTERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.96	1.2	V
		$V_{GS} = 0 V,$ $I_{S} = 20 A$	T <sub>J</sub> = 125°C		0.87		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 20 \text{ A}$			12.5		ns
Charge Time	t <sub>a</sub>				7.7		1
Discharge Time	t <sub>b</sub>				4.8		1
Reverse Recovery Charge	Q <sub>RR</sub>				4.4		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>				0.66		nΗ
Drain Inductance	L <sub>D</sub>	T 0500			0.20		1
Gate Inductance	L <sub>G</sub>	T <sub>A</sub> = 25°C			1.5		1
Gate Resistance	$R_{G}$				2.0	3.0	Ω

<sup>5.</sup> Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

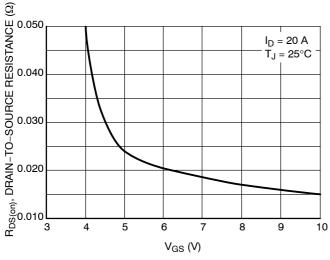
### **TYPICAL CHARACTERISTICS**



50  $V_{DS} \ge 10 \text{ V}$ 40 ID, DRAIN CURRENT (A) 30 20 25°C 10 = -55°C 0 1.0 1.5 2.0 2.5 3.0 3.5 4.0 V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



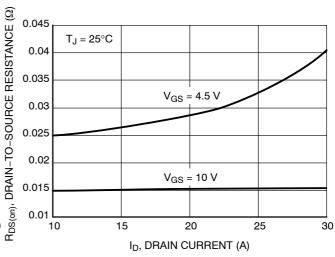
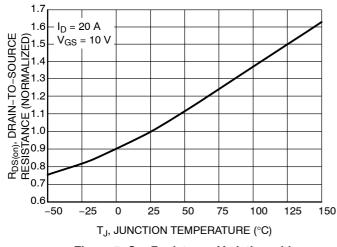


Figure 3. On-Resistance vs. V<sub>GS</sub>

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



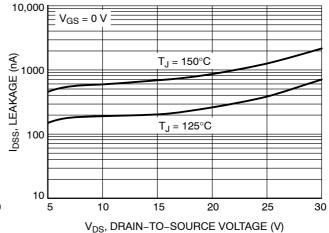


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

### **TYPICAL CHARACTERISTICS**

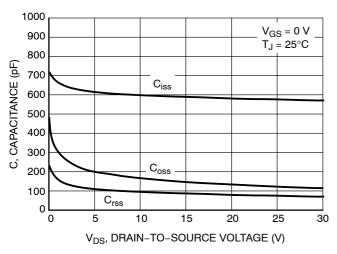


Figure 7. Capacitance Variation

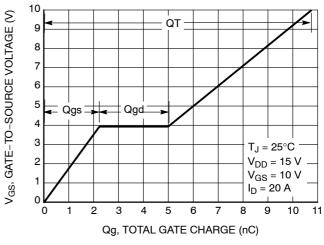


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

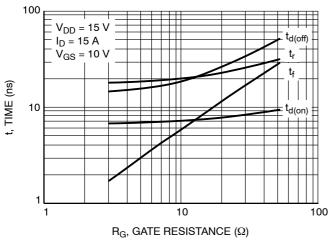


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

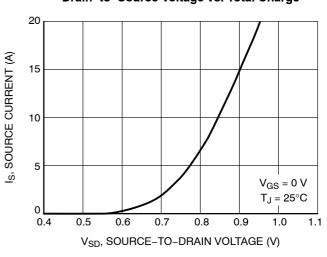


Figure 10. Diode Forward Voltage vs. Current

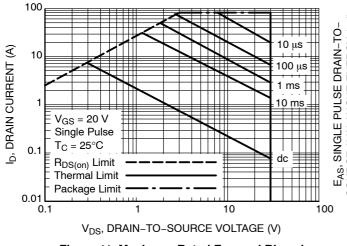


Figure 11. Maximum Rated Forward Biased Safe Operating Area

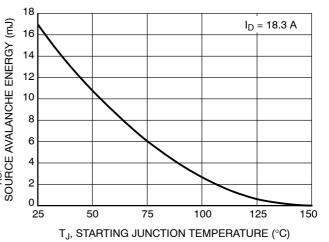


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

### **TYPICAL CHARACTERISTICS**

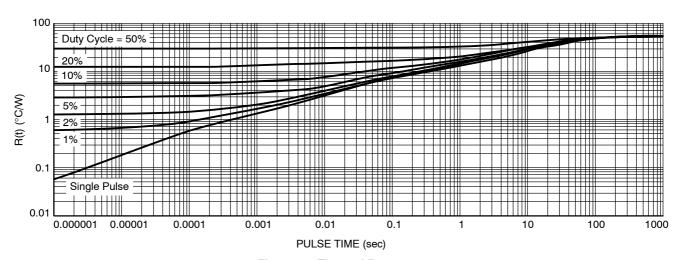
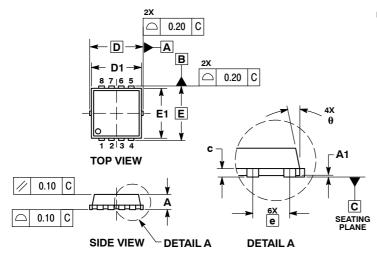


Figure 13. Thermal Response

### PACKAGE DIMENSIONS

### WDFN8 3.3x3.3, 0.65P CASE 511AB-01 **ISSUE B**

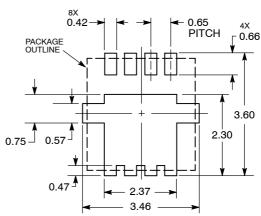


#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		C	.130 BSC	)	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
е		0.65 BSC	;	0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.64			0.025			
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	

#### **SOLDERING FOOTPRINT\*** 8x b В 0.10 С Α



DIMENSION: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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